

# DFT and Quantum Transport Simulations of 2D Material-Based Resistive Memories

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Grenoble, France



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Grenoble Alpes

 **UNIVERSITÉ  
SAVOIE  
MONT BLANC**

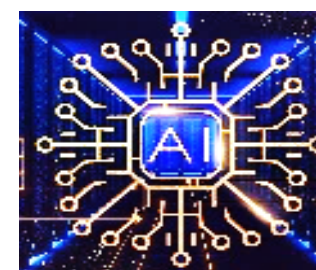
# 2D materials for future nanoelectronics and memories

## Non volatile memories



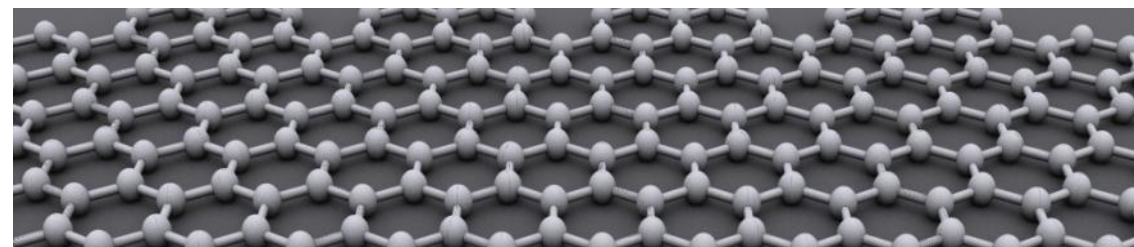
- Resistive RAM – **ReRAM**
- Magnetic RAM – **MRAM**
- Ferroelectric RAM – **FeRAM**

## Applications of 2D based memories



- integration for **high density** memories
- **neuromorphic** computing: **artificial intelligence**
- radio frequency **switches**
- **in-memory** computing

## 2D material important properties



- atomic **thickness** < 1nm
- absence of **dangling bonds**
- mechanical **flexibility**
- different materials with different properties: **metallic** (TMDs in 1T phase...), **insulating** (hBN...), **semiconducting** (TMDs in 2H phase...), **semi-metallic** (graphene), **ferroelectric** (TMDs,  $\text{In}_2\text{Se}_3$ ,...), **ferromagnetic** ( $\text{CrI}_3$ ,  $\text{Cr}_2\text{GeTe}_2$ ,  $\text{Fe}_2\text{GeTe}_2$ ...), **multiferroic** ( $\text{CuCrP}_2\text{S}_6$ ,  $\text{Cr}_2\text{Ge}_2\text{Se}_6$ ...)

## Advantages

- **stacking** in **van der Waals** heterostructures
- small amount of material is necessary: **sustainability**
- good electrostatic control: **low switching voltages**
- low power consumption: **green electronics**

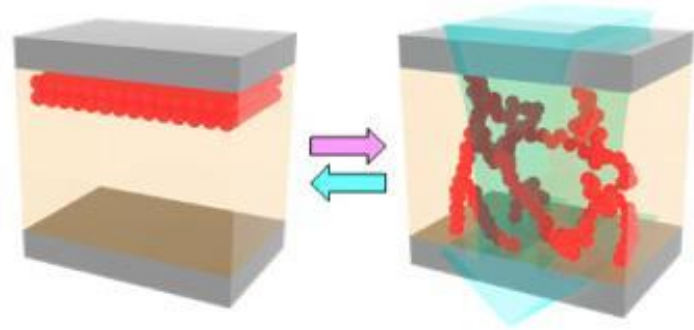


## Challenges

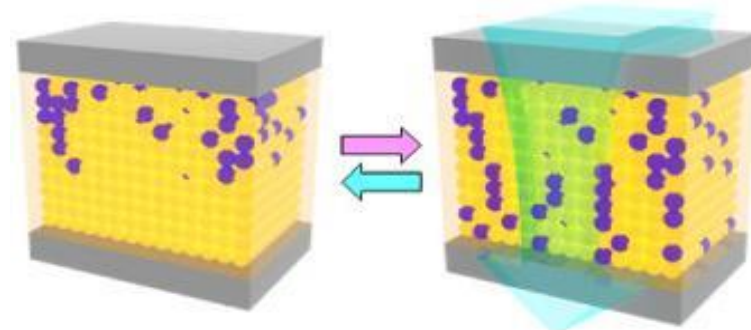
- **large scale and size fabrication**
- **variability** due to defects, polycrystallinity, stability...
- limited **CMOS** compatibility

# Resistive memories based on 2D materials

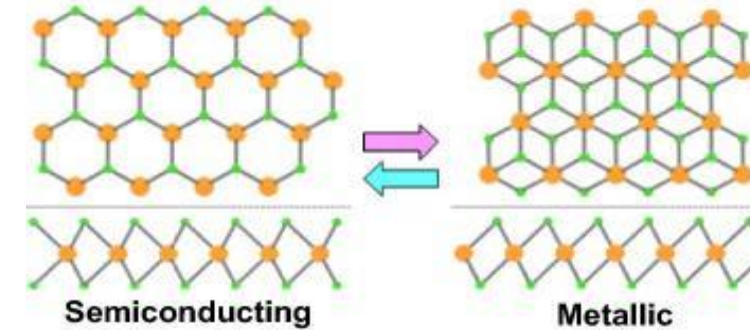
## Filament formation



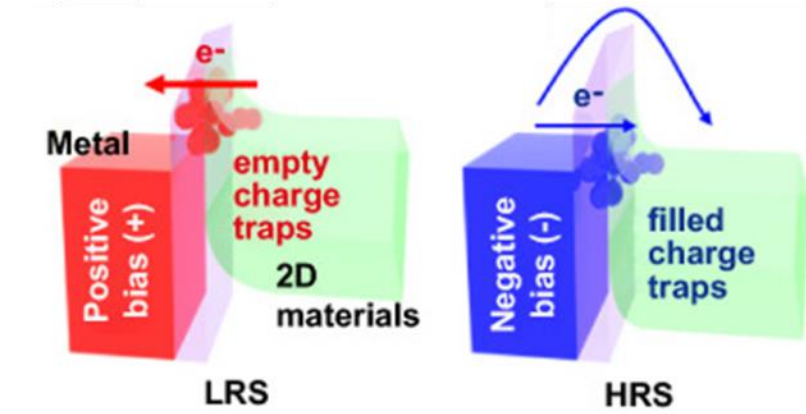
## Vacancy migration



## Phase transition



## Charge trapping

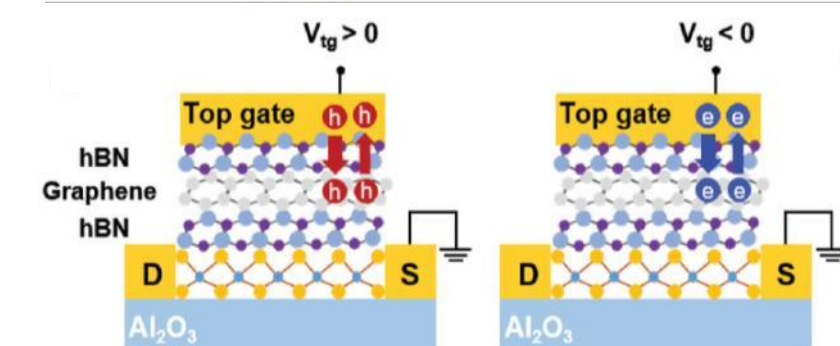
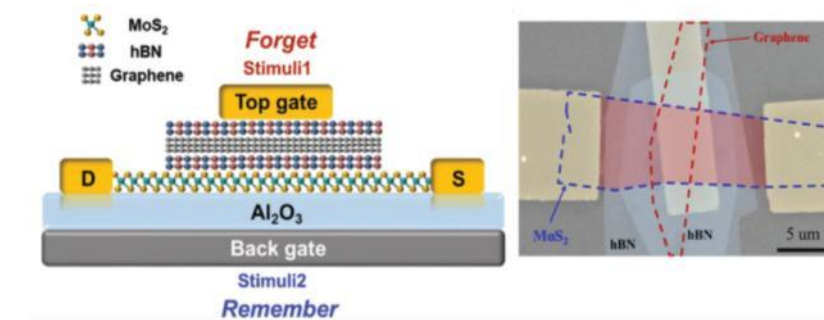
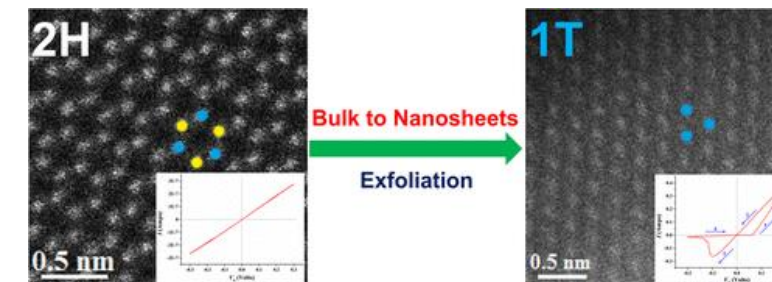
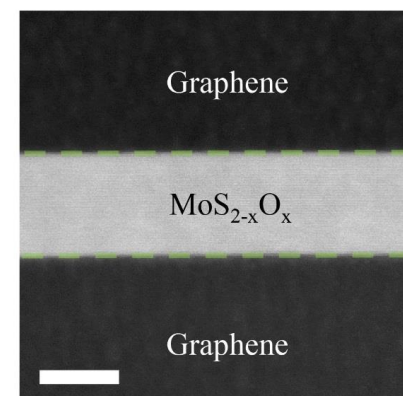
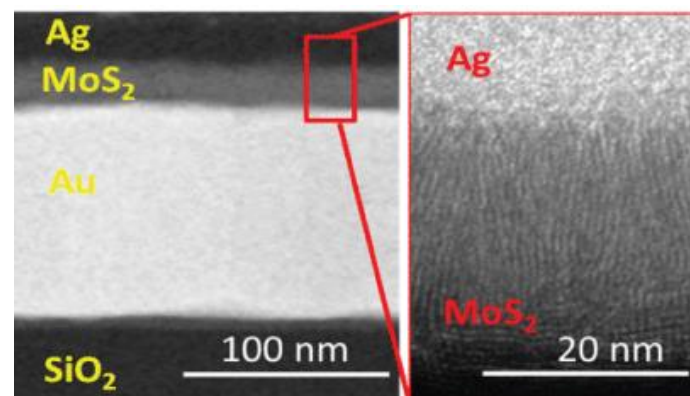


Ag/MoS <sub>2</sub> /Ag	IEDL <b>41</b> , 936 (2020)
Cu/MoS <sub>2</sub> /Au	Nano Lett. <b>19</b> , 2411 (2019)
Ni/Au/MoS <sub>2</sub> /Gr	IScience <b>23</b> , 101676 (2010)
Ag/ZrO <sub>2</sub> /WS <sub>2</sub> /Pt	ACS Appl. Mater. Interfaces <b>11</b> , 48029 (2019)

Pd/WS <sub>2</sub> /Pt	Small <b>15</b> , 1901423 (2019)
Gr/MoS <sub>2-x</sub> O <sub>x</sub> /Gr	Nat. Electron. <b>1</b> , 130 (2018)
Ag/WO <sub>3-x</sub> Au/WSe <sub>2</sub> /Gr	Adv. Mater. <b>30</b> , 1801447 (2018)
Ag/MoO <sub>x</sub> /MoS <sub>2</sub> /Ag	Nat. Mater. <b>14</b> , 199 (2015)

Au/MoS <sub>2</sub> /Au	Nat. Mater. <b>18</b> , 141 (2019)
Ti/Ni/MoTe <sub>2</sub> /Ti/Au	Nat. Mater. <b>18</b> , 55 (2019)
Ag/MoS <sub>2</sub> /Gr	Nano Lett. <b>16</b> , 572 (2016)

Cr/Au/hBN/Gr/hBN/MoS <sub>2</sub> /Al <sub>2</sub> O <sub>3</sub>	Adv. Sci. <b>6</b> , 1901072 (2019)
Ti/Au/WSe <sub>2</sub> /WCL/hBN/Pt/Au	Nat. Comm. <b>9</b> , 5106 (2018)
Cr/Au/MoS <sub>2</sub> /hBN/Gr	Adv. Sci. <b>6</b> , 1901072 (2019)



[D. Dev *et al.*, IEDL **41**, 936 (2020)]

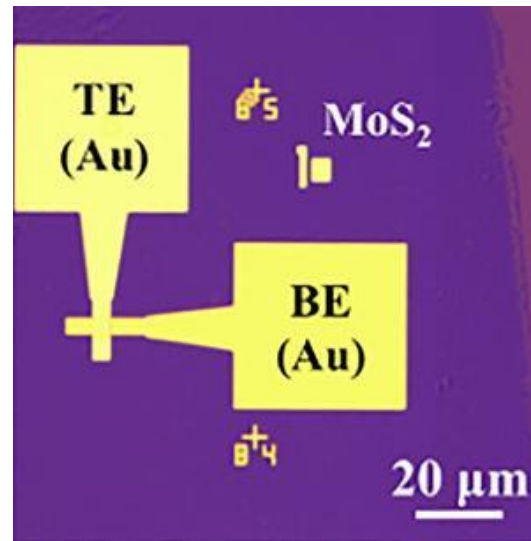
[M. Wang *et al.*, Nat. Elect. **1**, 130 (2018)]

[P. Cheng *et al.*, Nano Lett. **16**, 572 (2016)]

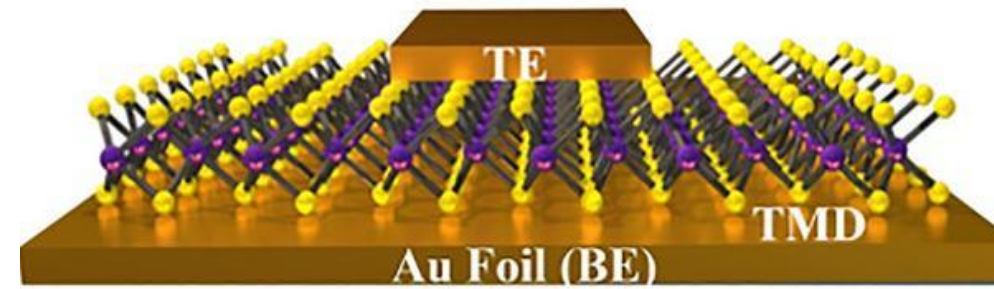
[H. Chen *et al.*, Adv. Sci. **6**, 1901072 (2019)]

# Atomritors

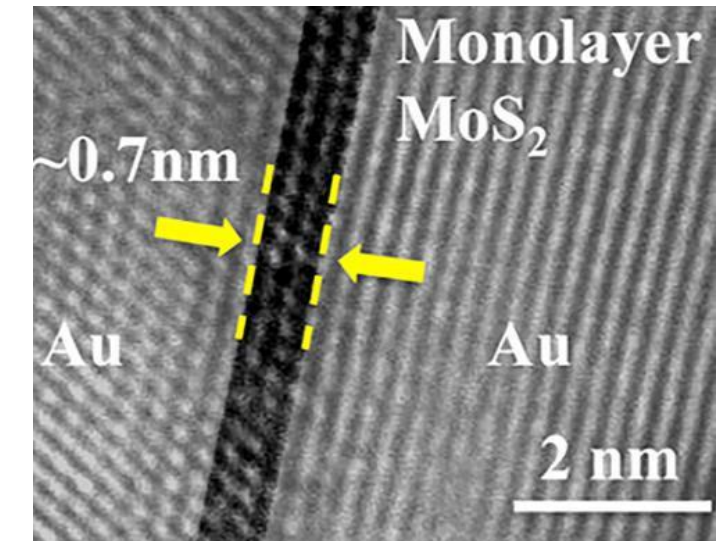
First realization of an atomistor: R. Ge, X. Wu, M. Kim, J. Shi, S. Sonde, L. Tao, Y. Zhang, J. C. Lee and D. Akinwande, Nano Lett. **18**, 434 (2018)



Optical image of metal-insulator-metal structures of TMD crossbar sandwich.

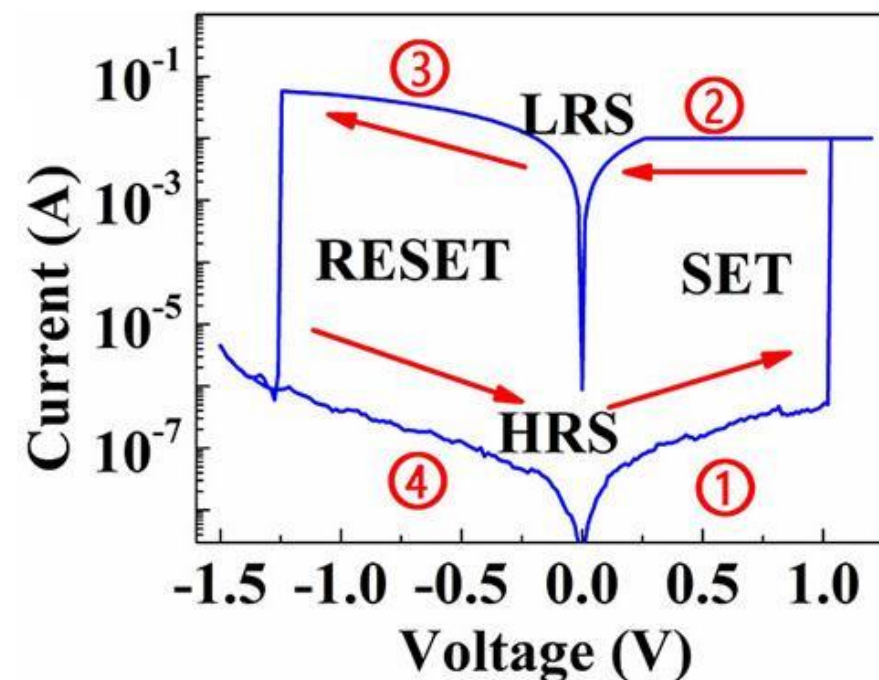


Schematic of TMD lithography-free and transfer-free sandwich.

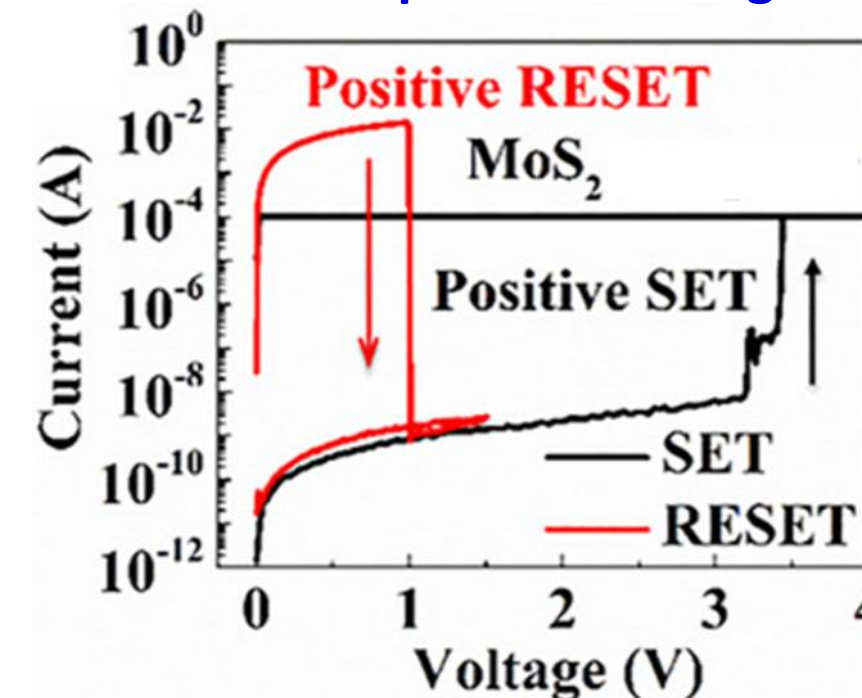


TEM cross-section image of Au/MoS<sub>2</sub>/Au litho-free device revealing the atomically sharp and clean monolayer interface.

## Bipolar switching

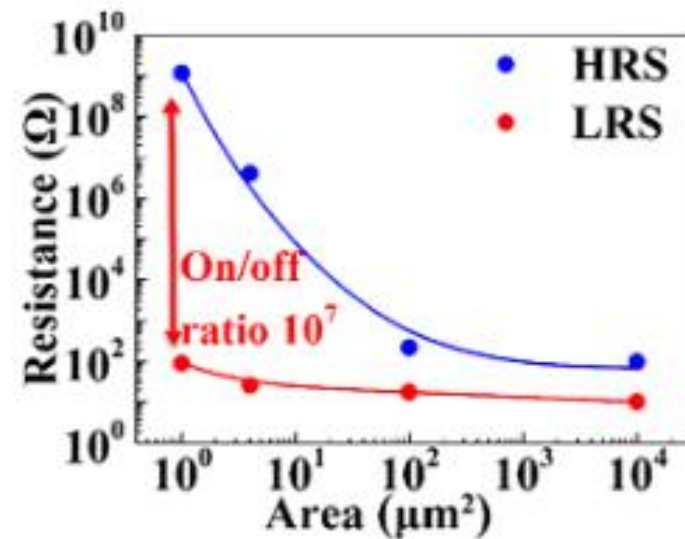


## Unipolar switching



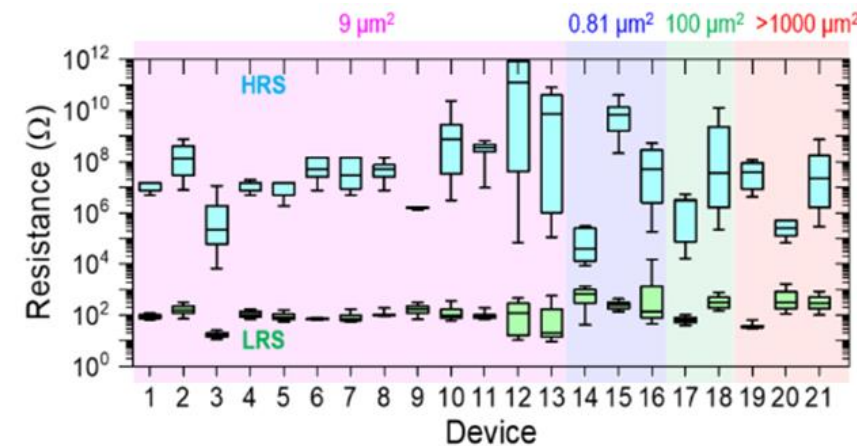
# Properties of the high resistance state (HRS)

Generally, the **resistance decreases with device area...**



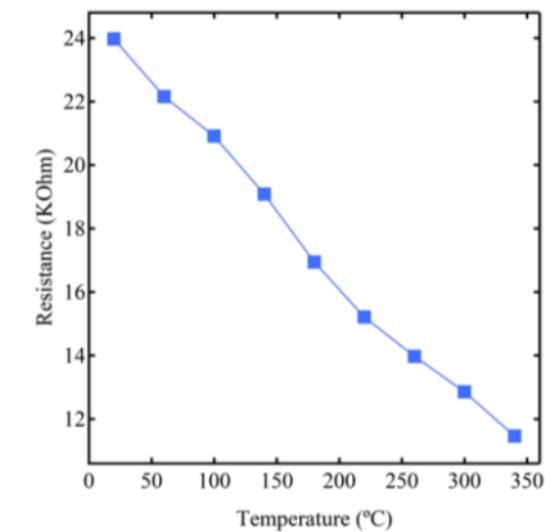
[Nano Lett. **18**, 434 (2018)]

Up to **8 orders** of magnitude of **device-to-device variability** and...



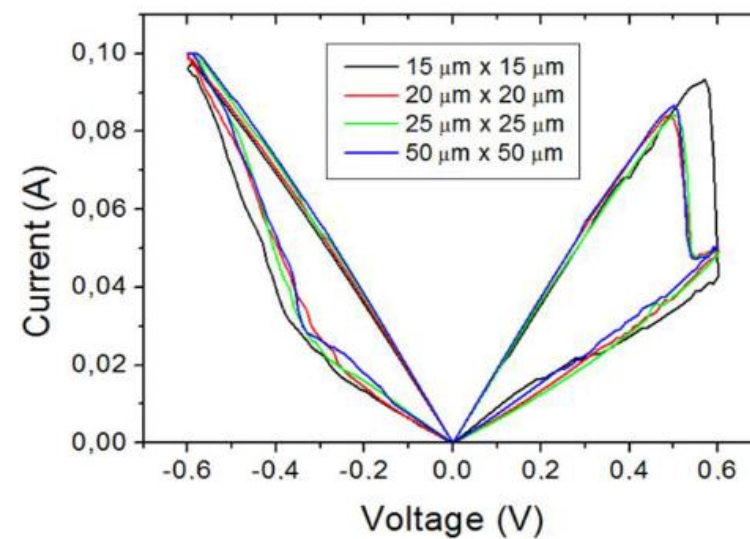
[Nat. Elect. **7**, 557 (2024)]

Generally, the **resistance decreases with temperature...**



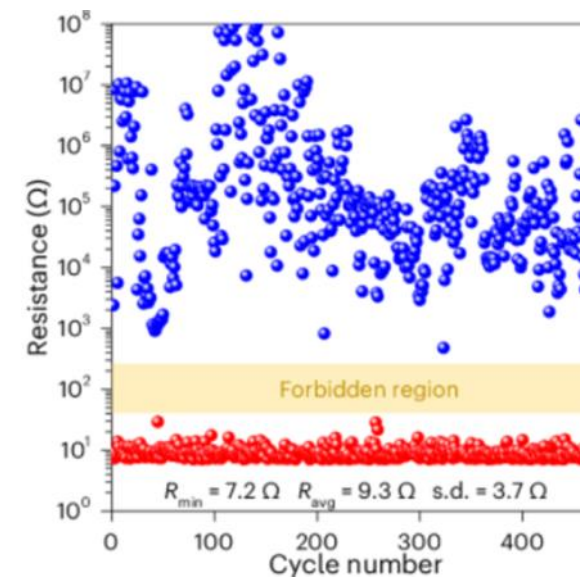
[Nat. Elect. **1**, 130 (2018)]

...but **not always**



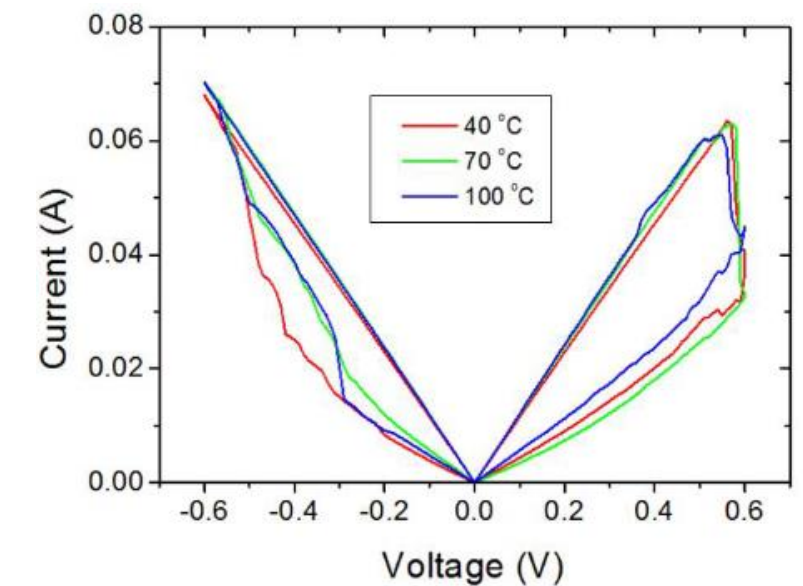
[Adv. Funct. Mater. **27**, 1604811 (2017)]

...**5 orders** of magnitude of **cycle-to-cycle variability**



[Nat. Elect. **7**, 557 (2024)]

...but **not always**



[Adv. Funct. Mater. **27**, 1604811 (2017)]

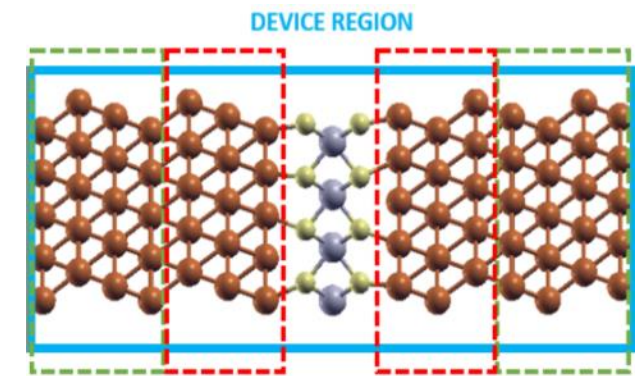
# Plan

Large variety of behaviors... Origin of the switching mechanism? What does determine the LRS and the HRS?  
How to optimize the performances?

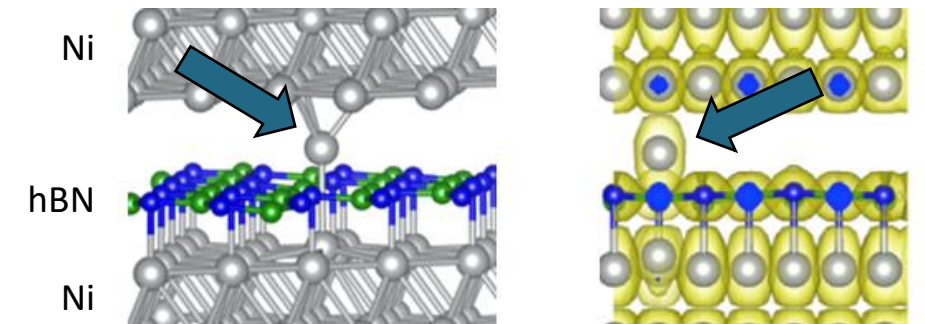
- Few words about the simulation methodology



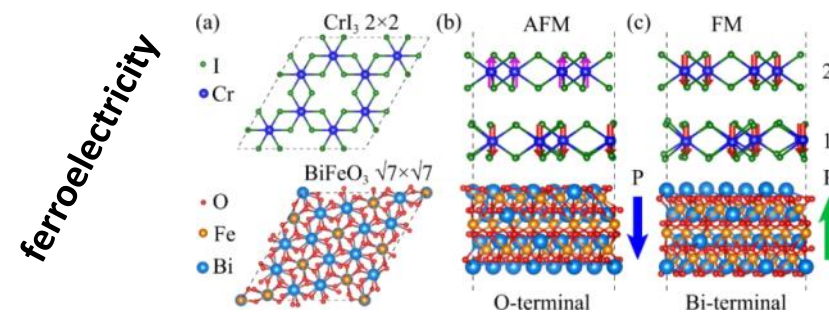
- HRS - Clean metal-2D heterojunctions with different materials and 2D layers



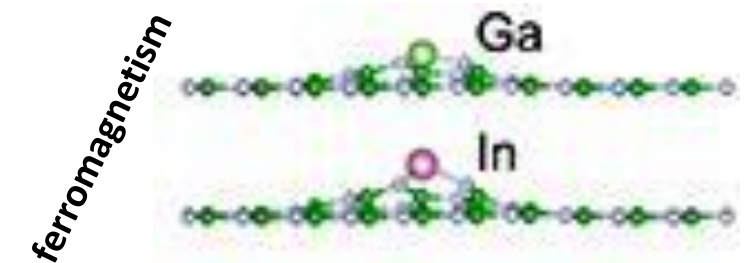
- LRS - Role of defects: the example of metal-ion substitution



- Perspectives we are interested in



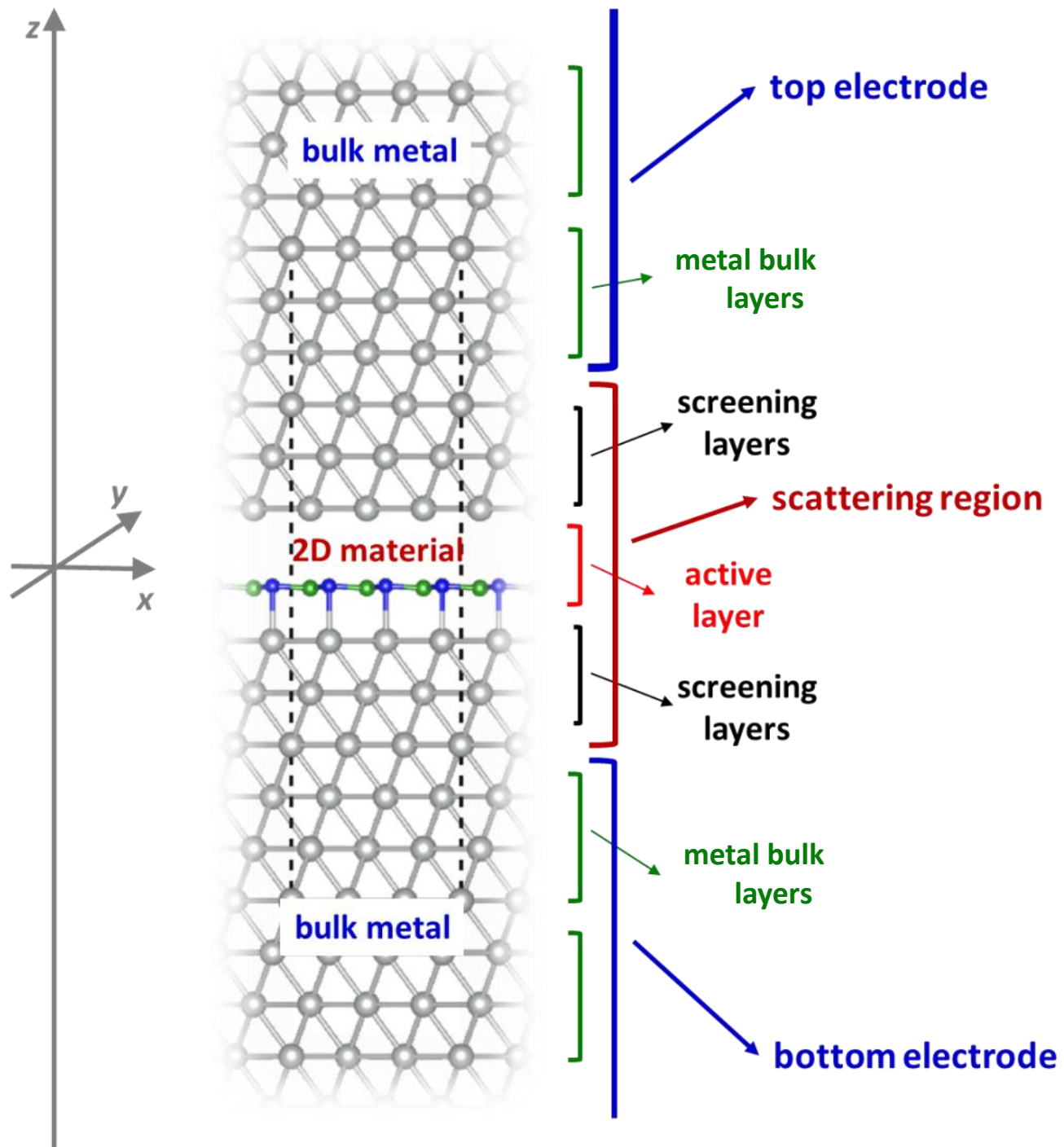
[npj Comput Mater **8**, 20 (2022)]



[2D Mater. **11**, 035019 (2024)]

# Methodology

## Vertical stacking



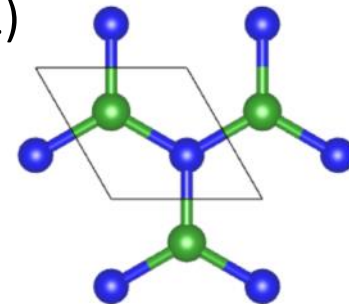
## Structural relaxation and electronic properties

### Density Functional Theory

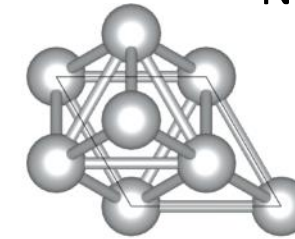


The “problem” of periodic primitive cell and **strain**

hBN (1x1)

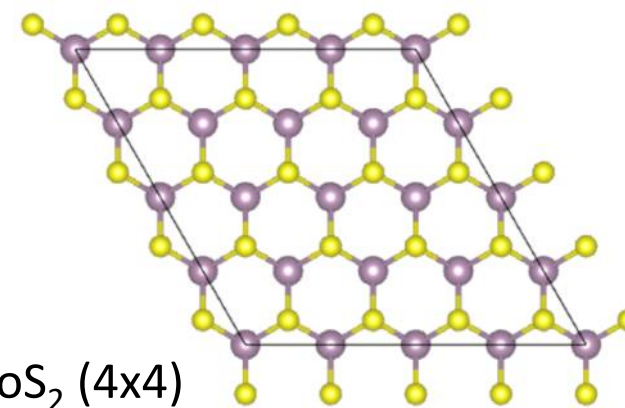


Ni(111) (1x1)

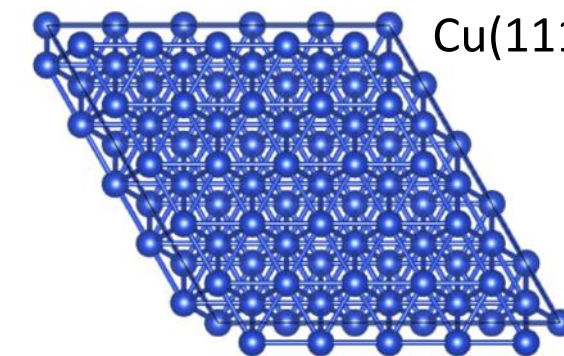


$$\epsilon (\text{hBN}) = -0.56\%$$

$$\epsilon (\text{Ni}) = 1.44\%$$



MoS<sub>2</sub> (4x4)



Cu(111) (5x5)

$$\epsilon (\text{MoS}_2) = 0.11\%$$

$$\epsilon (\text{Cu}) = -0.79\%$$

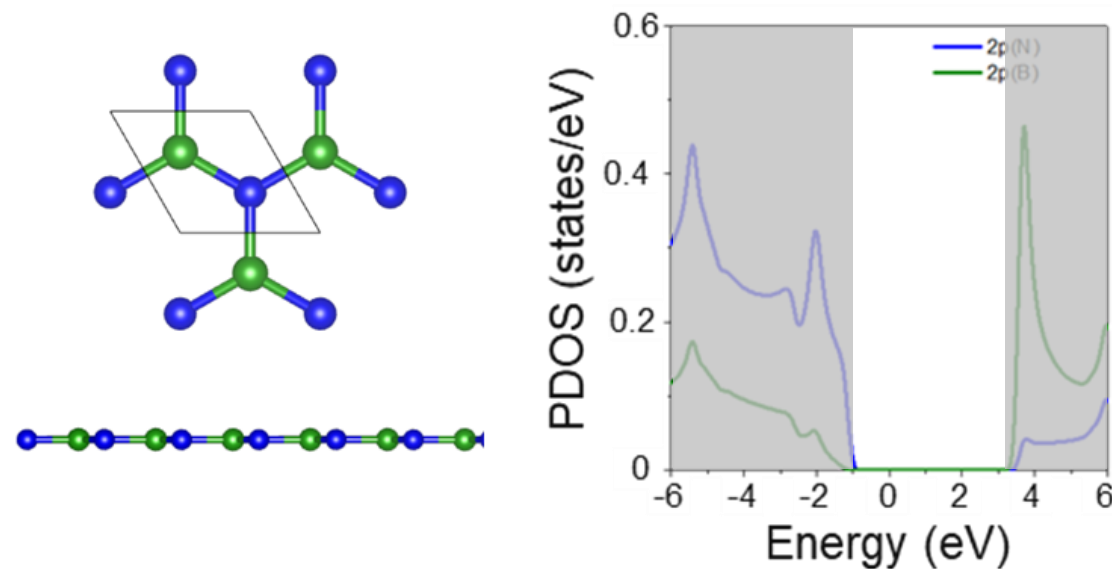
### Electron transport

### Non Equilibrium Green's Function



# Stacking modes in small cells (1x1 – Ni and hBN)

Free-standing hBN



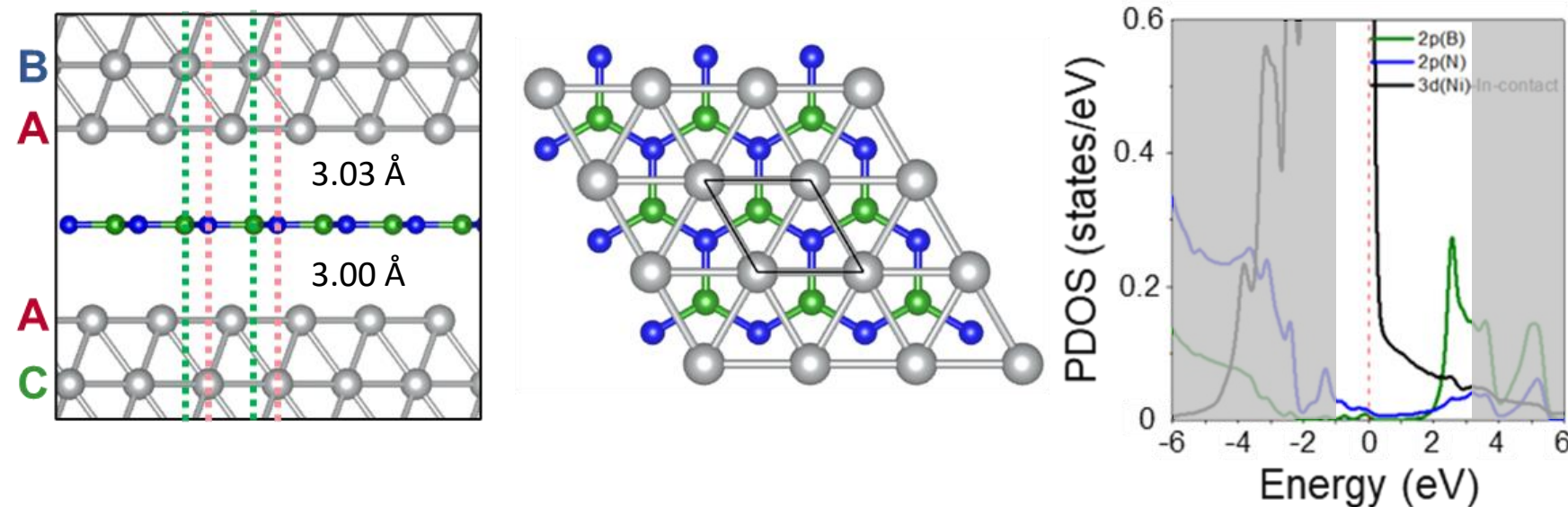
Free-standing hBN : gap  $\sim 4.5$  eV

**AA stacking:** hBN at the same distance from the electrodes, mid-gap states

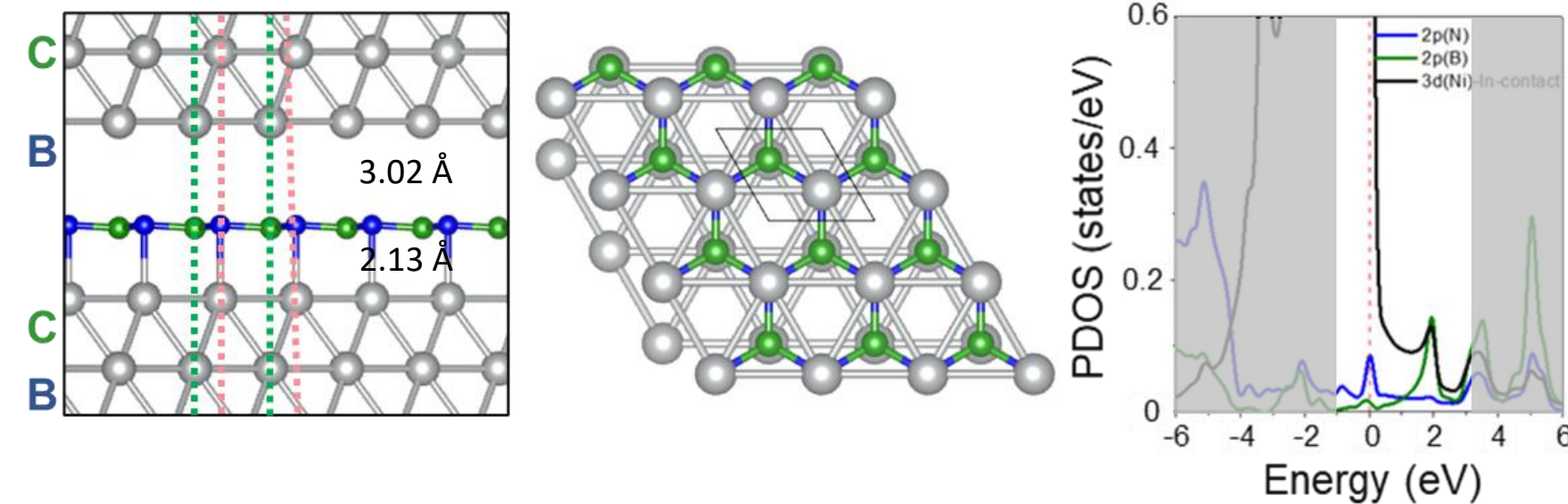
**CB stacking:** stronger Ni/N bond formation at one interface due to N affinity, different distances from the electrodes, stronger gap reduction

**Strong influence of the stacking mode**

AA stacking

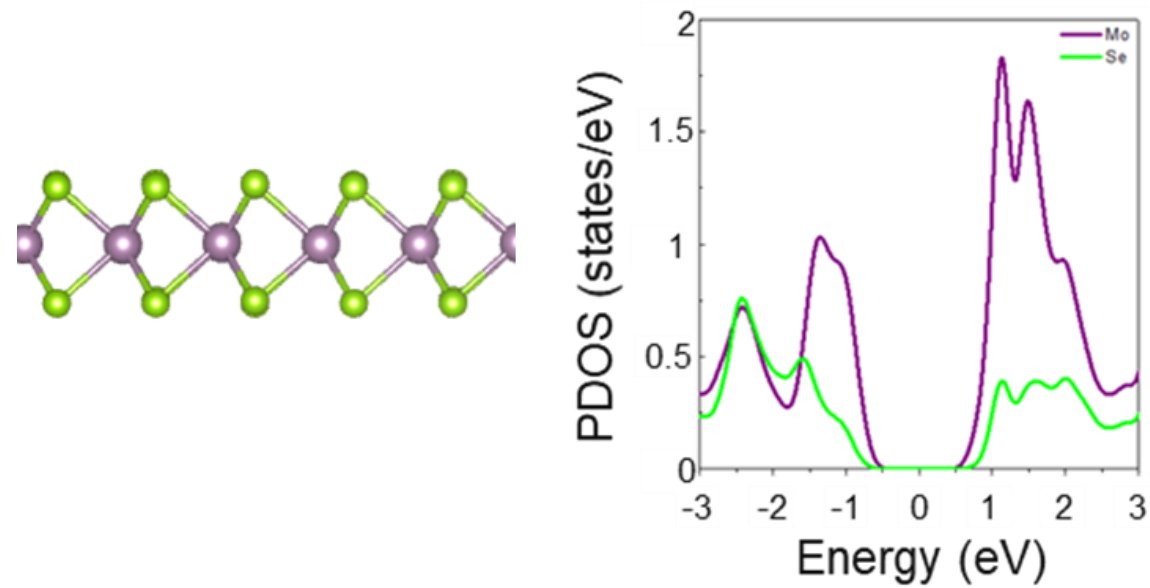


CB stacking



# Stacking modes in large cells (5x5 and 4x4 – Cu and MoS<sub>2</sub>)

Free standing MoS<sub>2</sub>



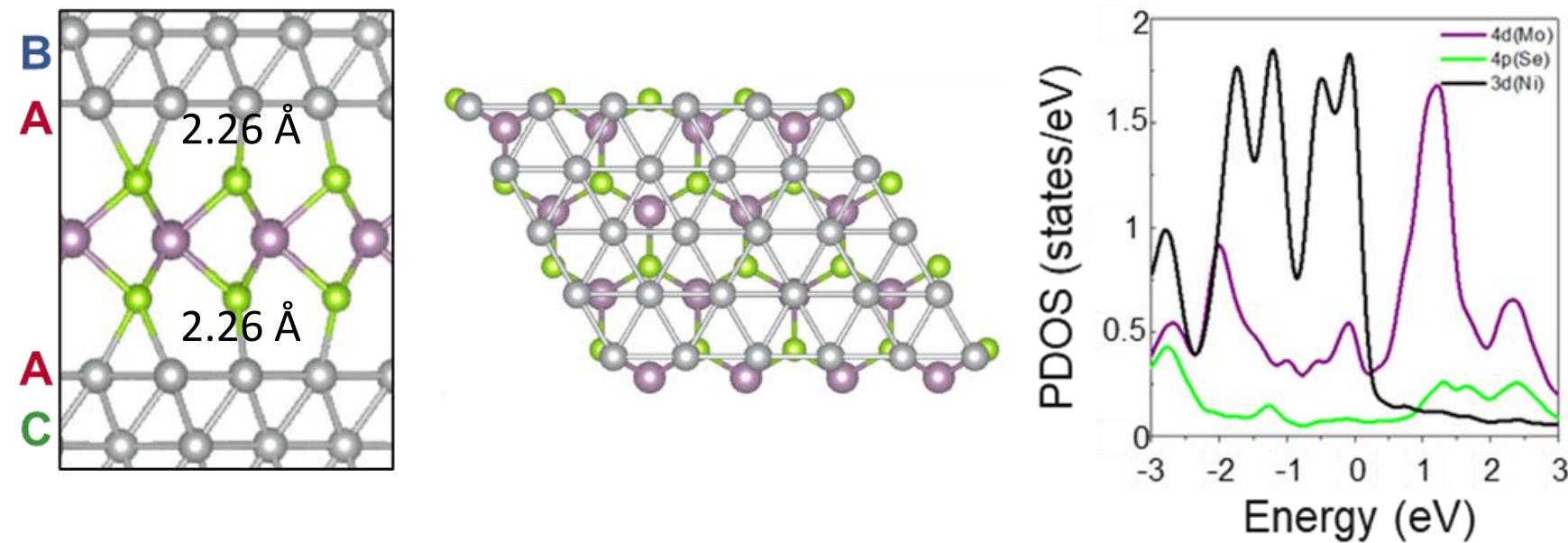
Free-standing MoS<sub>2</sub> : gap ~1.5 eV

Both AA and BA stacking: Ni/S bonds formation at the interface

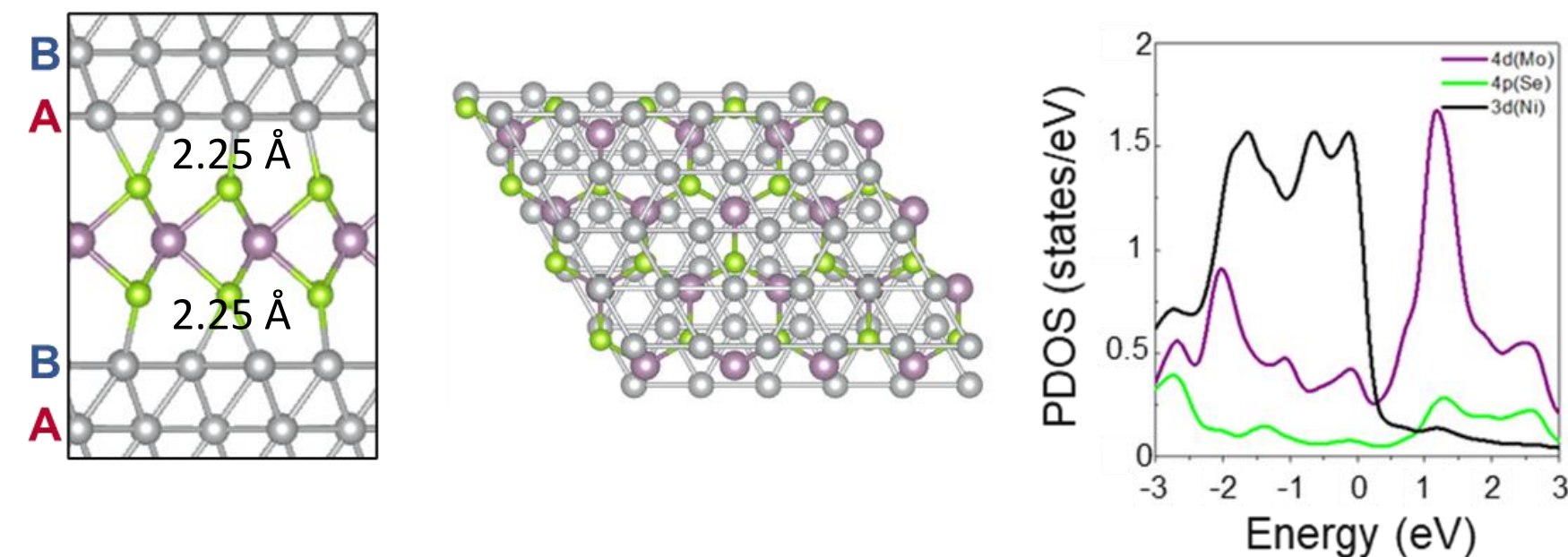
The gap is completely closed

Nearly same environment for S atoms at MoS<sub>2</sub>/Cu interfaces

AA stacking



BA stacking

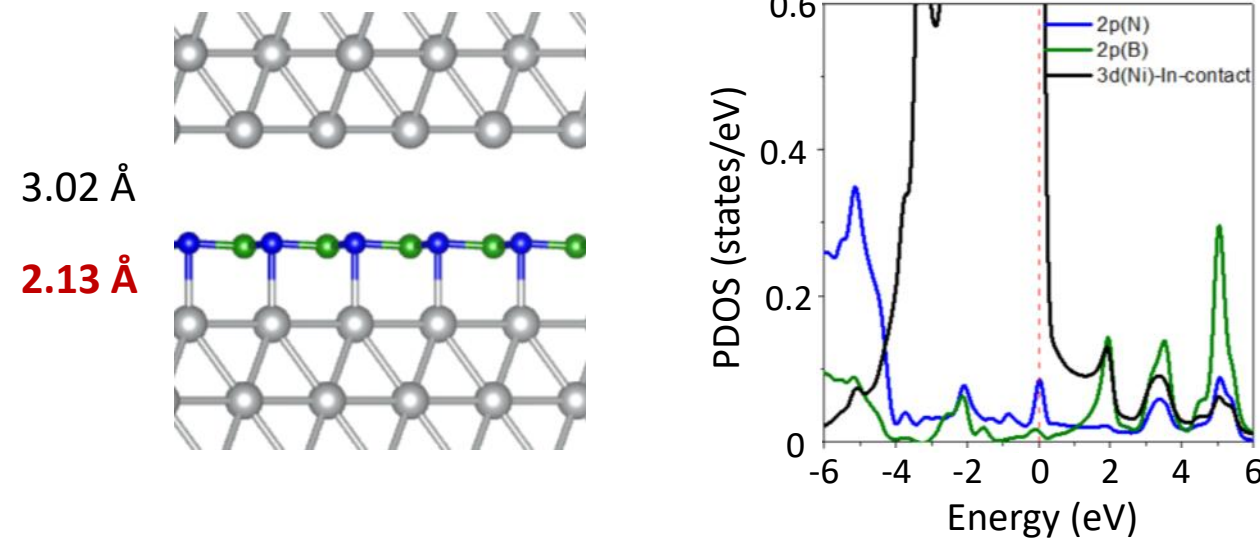


# Different materials

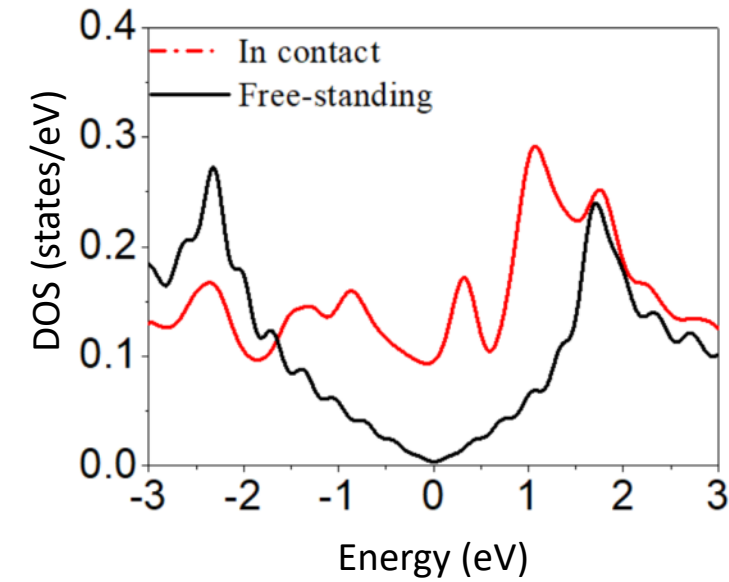
## Different electrode metal

## Different 2D material

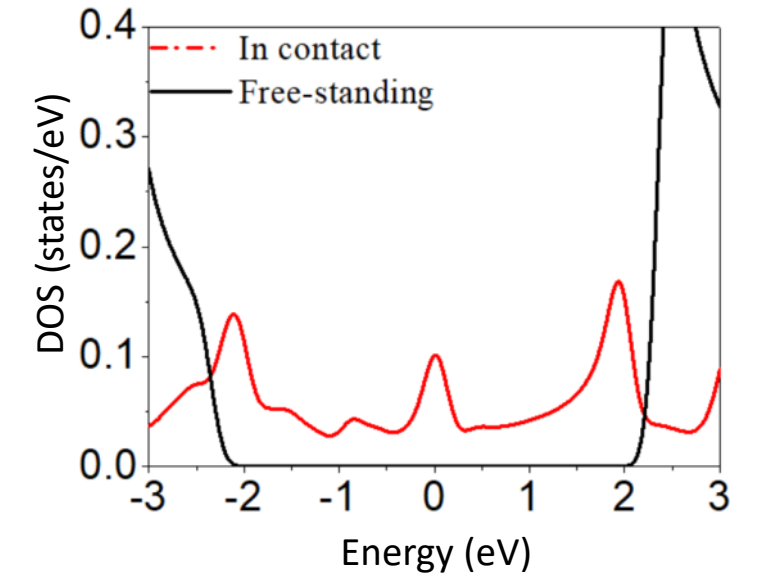
Ni/hBN/Ni



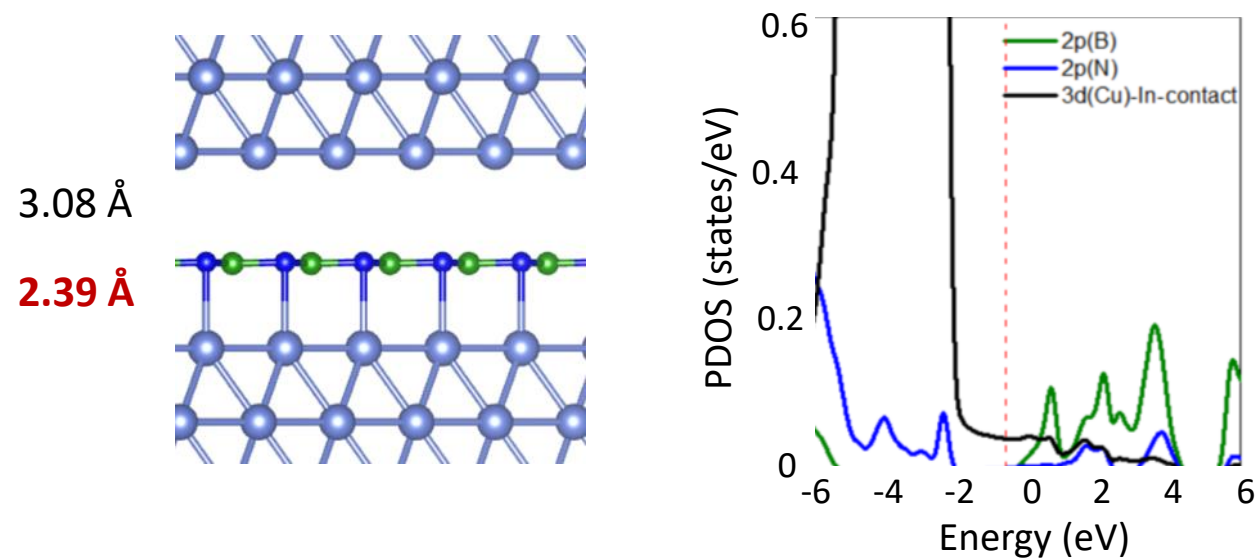
Ni/Graphene/Ni



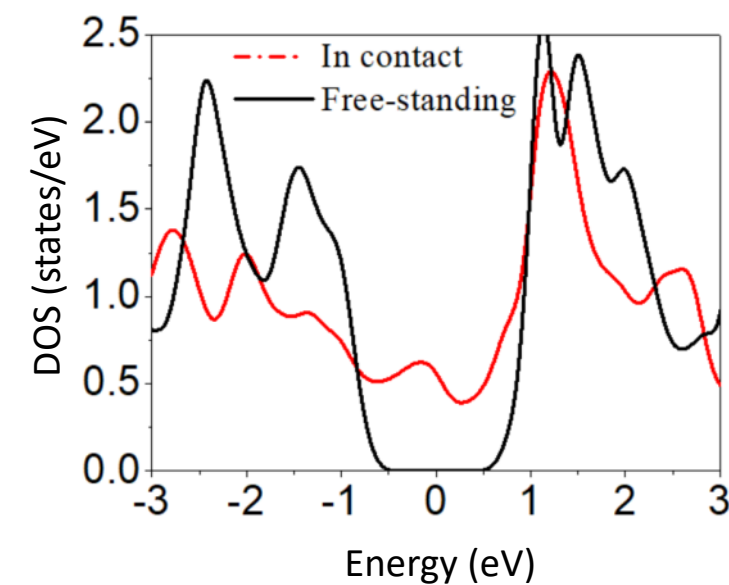
Ni/hBN/Ni



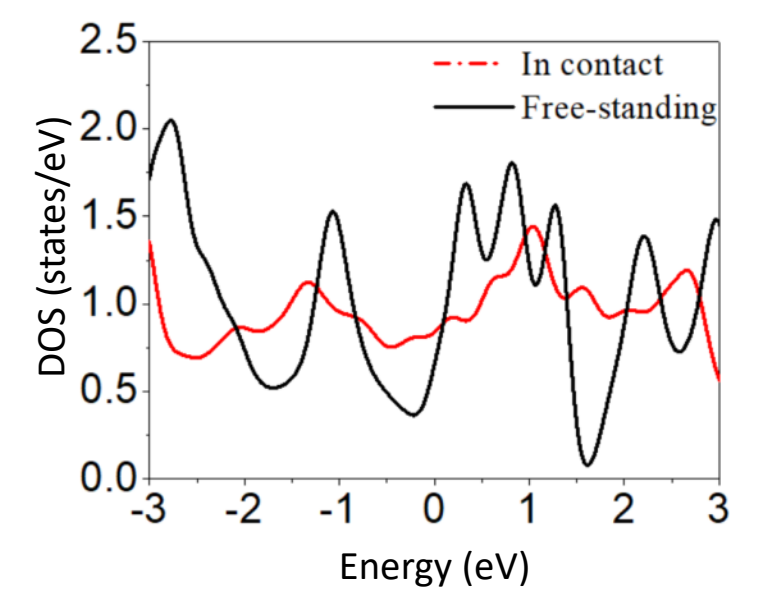
Cu/hBN/Cu



Ni/2H-MoSe<sub>2</sub>/Ni



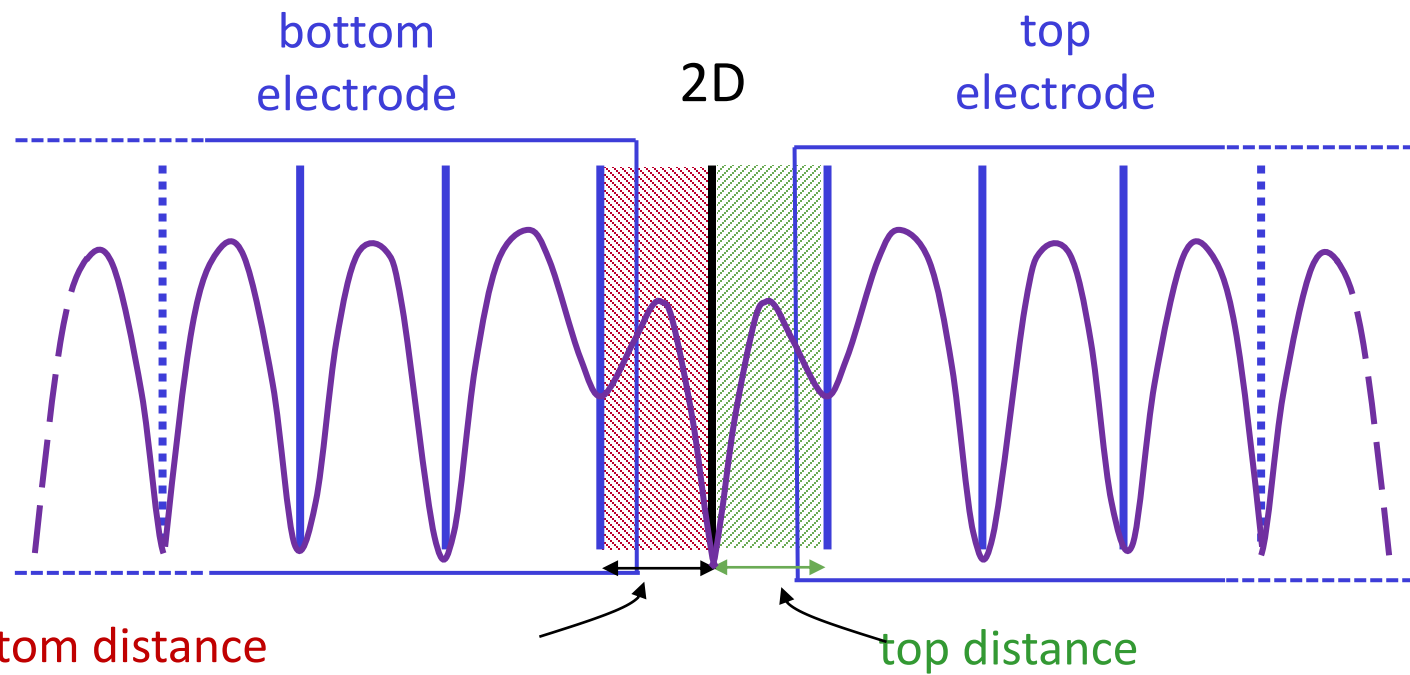
Ni/1T-MoSe<sub>2</sub>/Ni



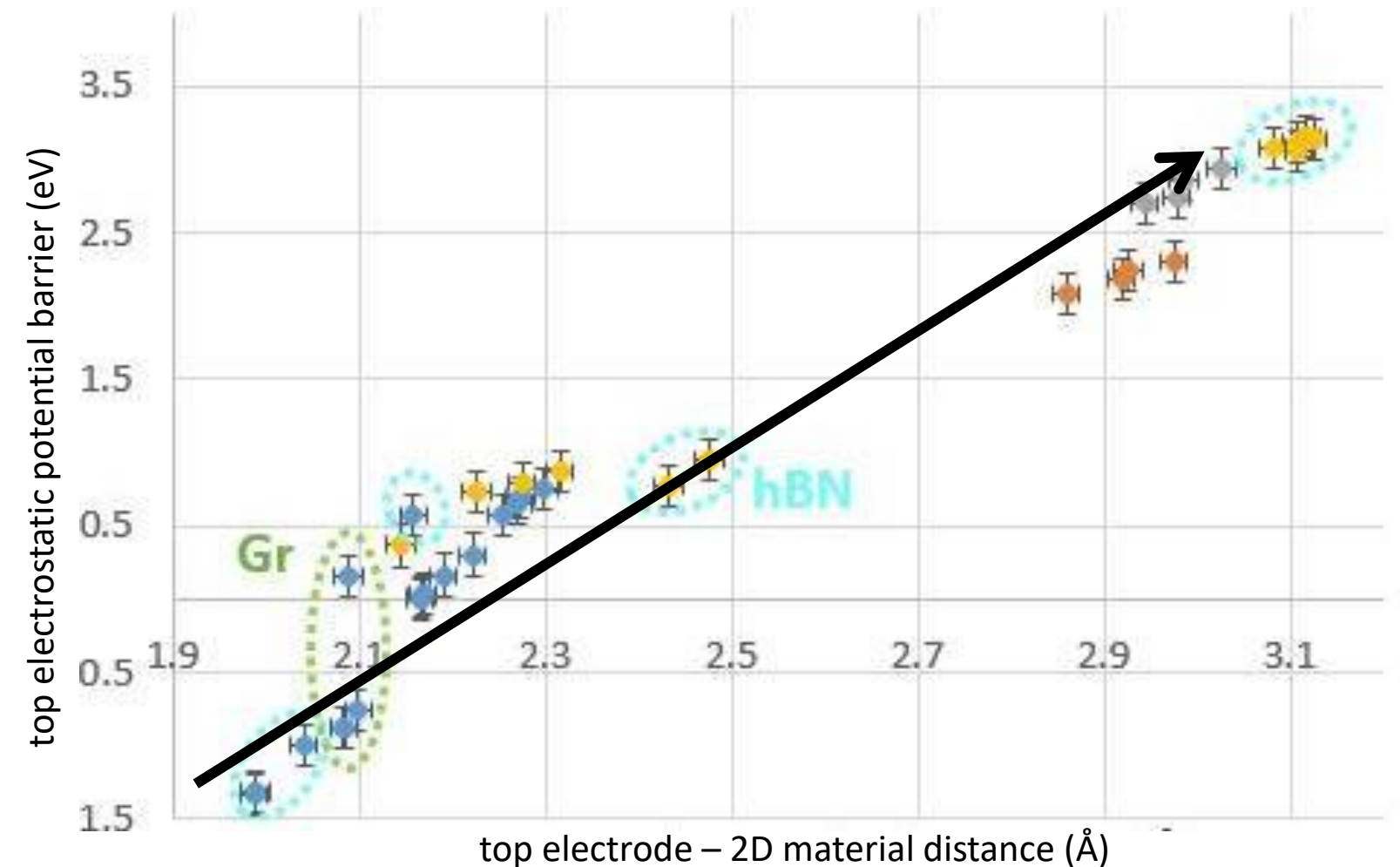
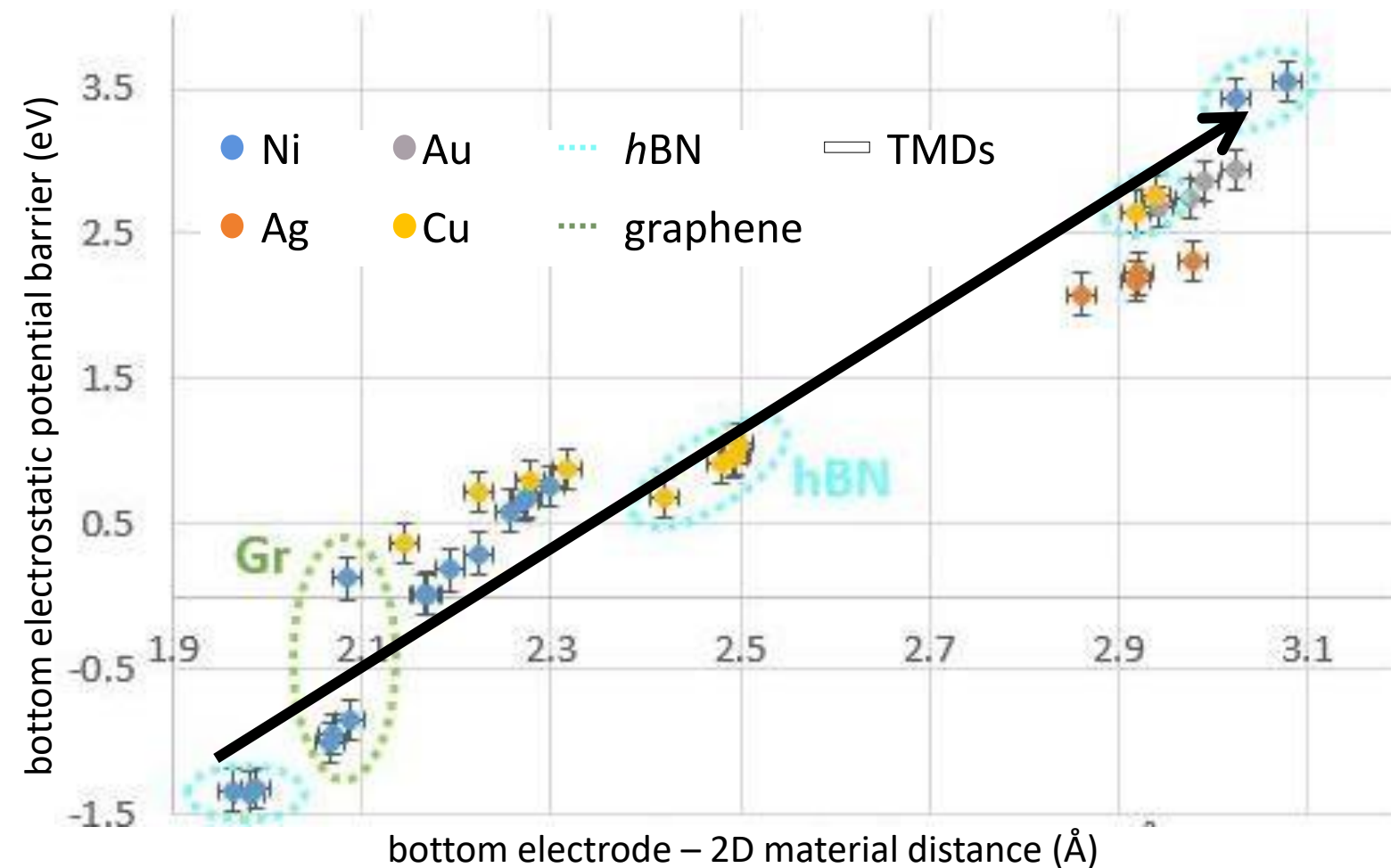
Larger charge transfer hBN/Ni than hBN/Cu

All 2D materials remain or become metallic

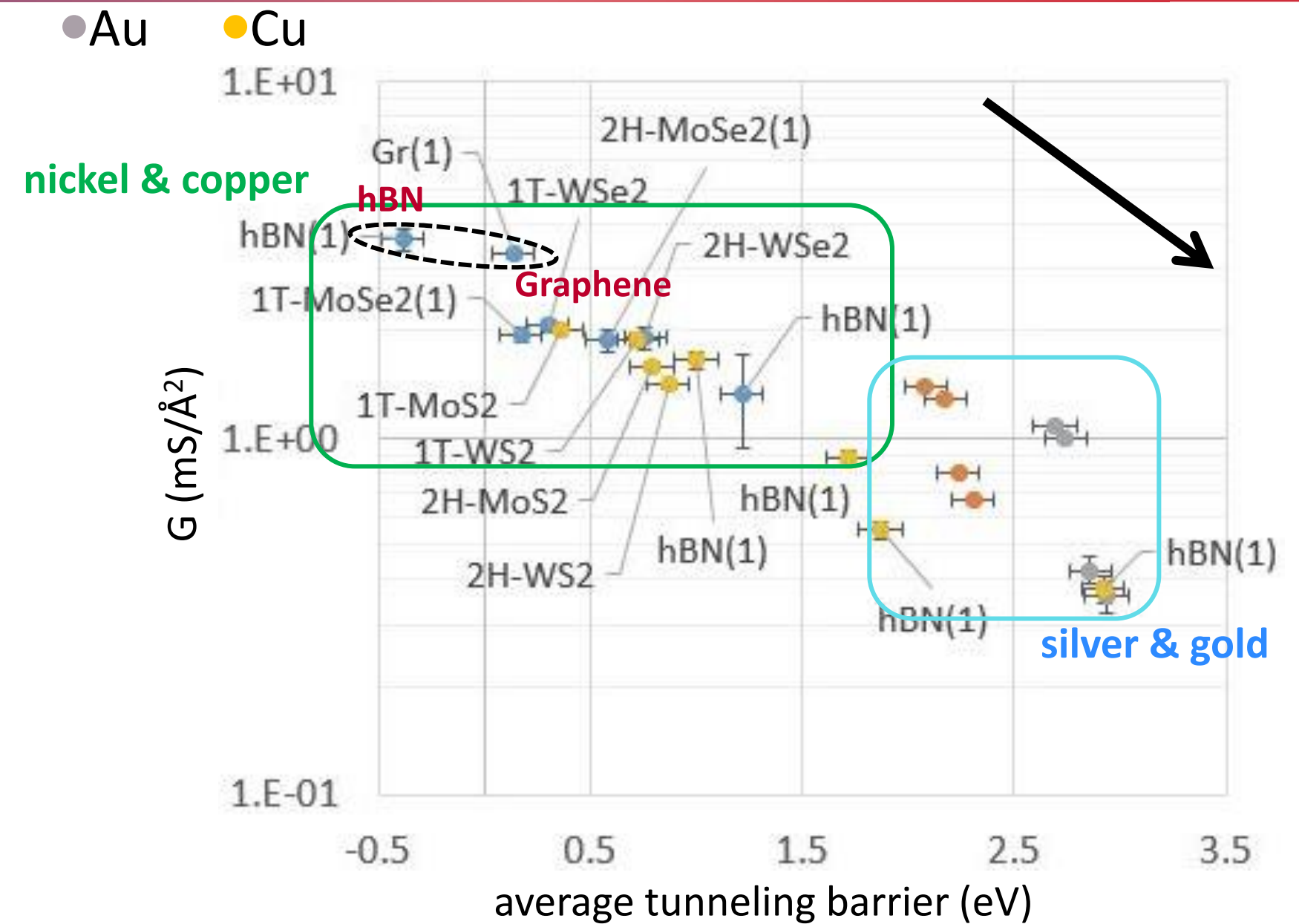
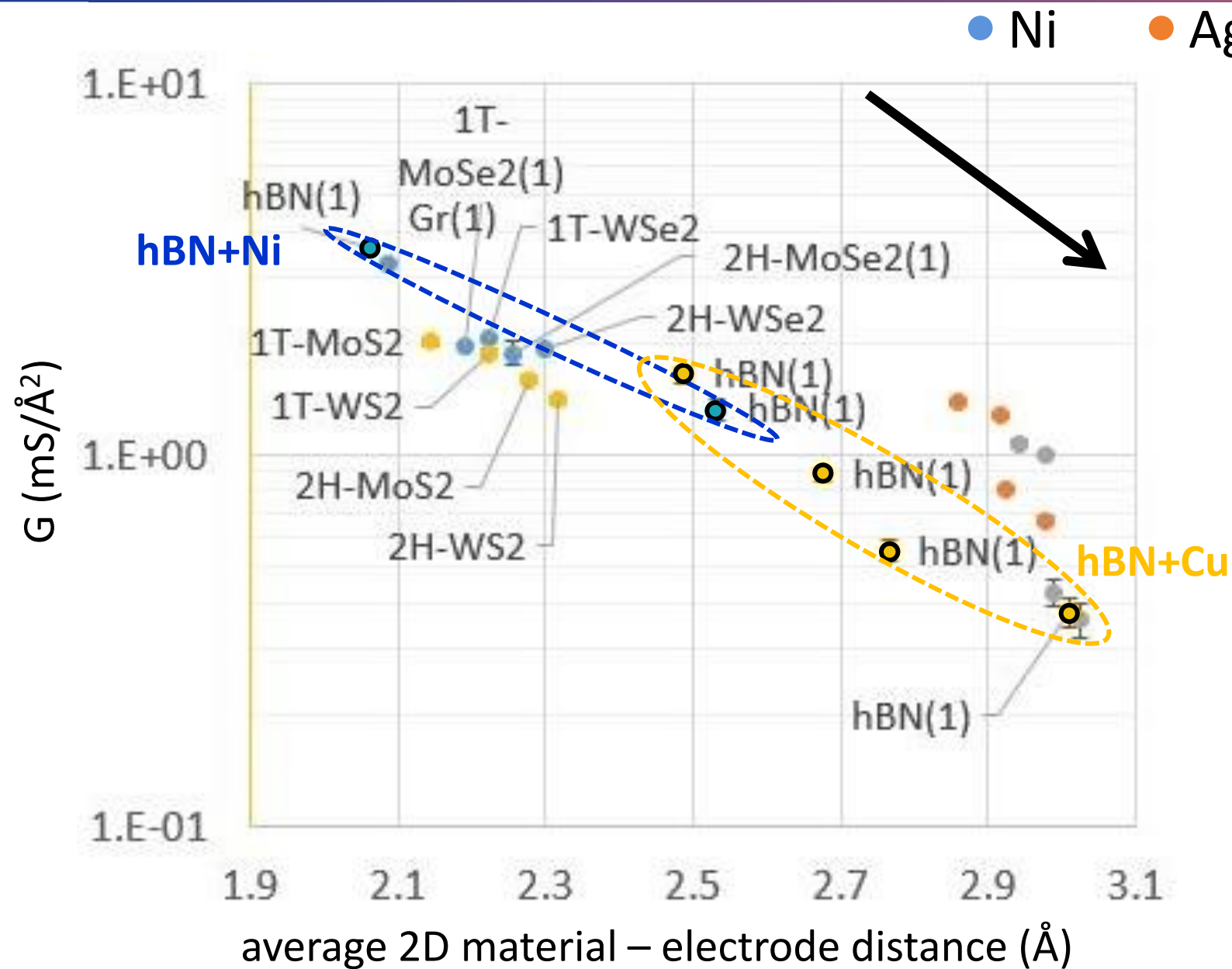
# Tunneling barrier



- Barrier height between -1.5 eV and 3 eV
- Higher for less-coupling bonds (hBN, Ag and Au)
- Increasing with distance between electrode and 2D material



# Conductance of devices with monolayers



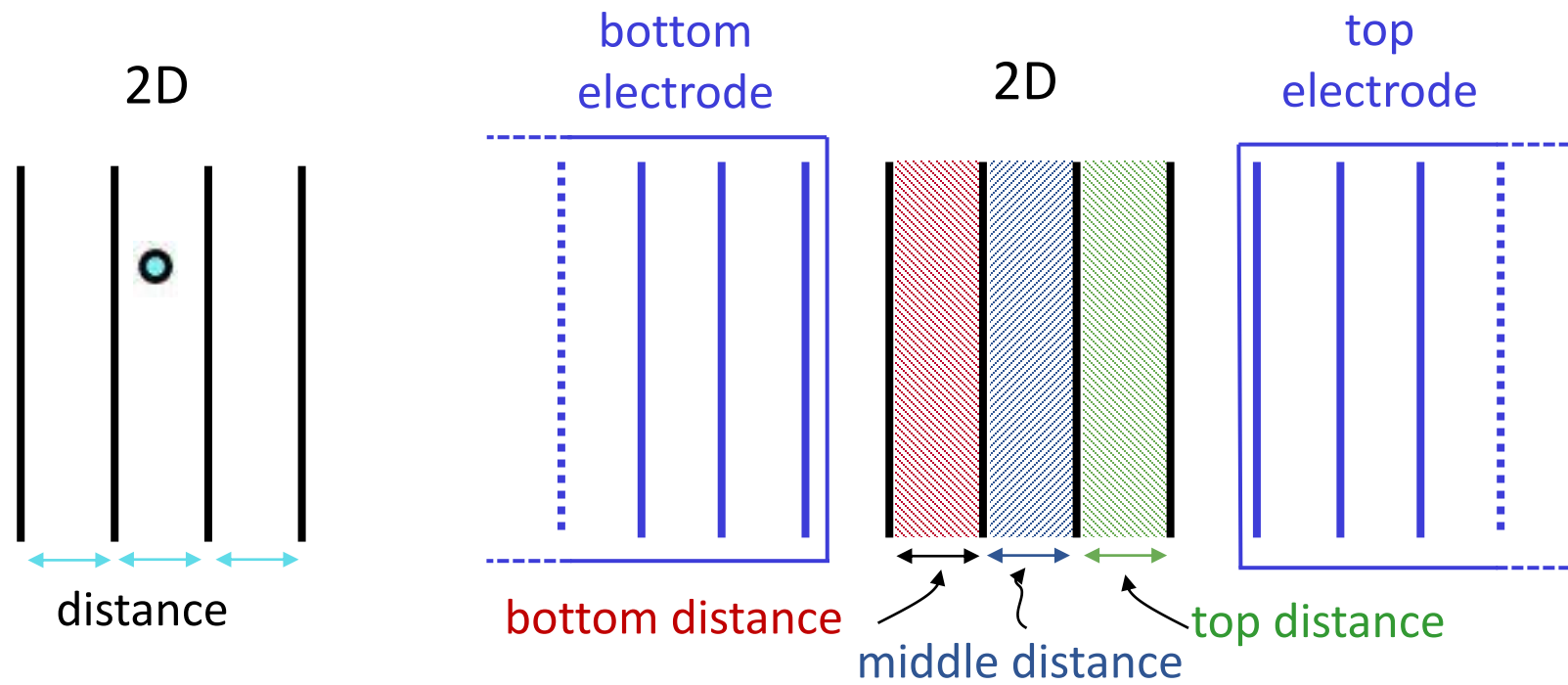
Conductance variations within **one order of magnitude**...

**Stacking** does not play an important role

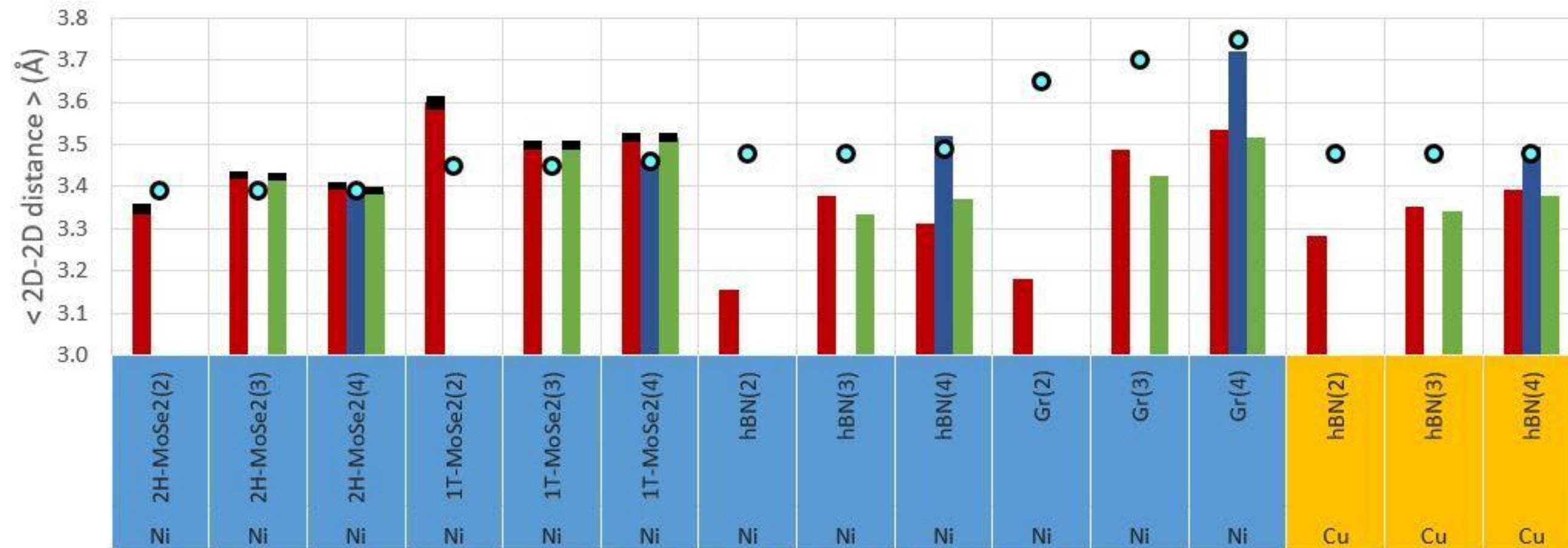
**Different materials** or **phases** do not play an important role (graphene vs hBN)

Only the **potential barrier** is important

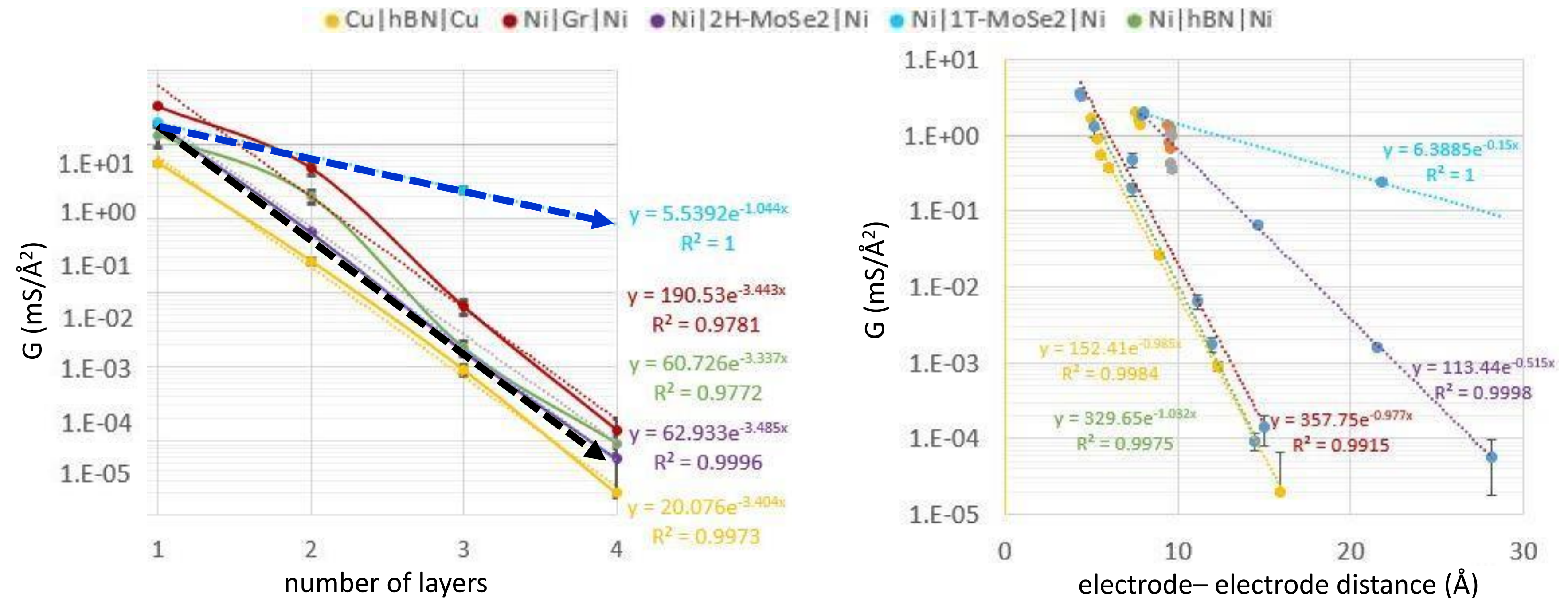
# 2D material - 2D material distance for multilayers



The **middle layers** behave as in the **isolated 2D materials**, while the **external layers** form **strong bonds** with the electrodes, thus decreasing the junction distance.



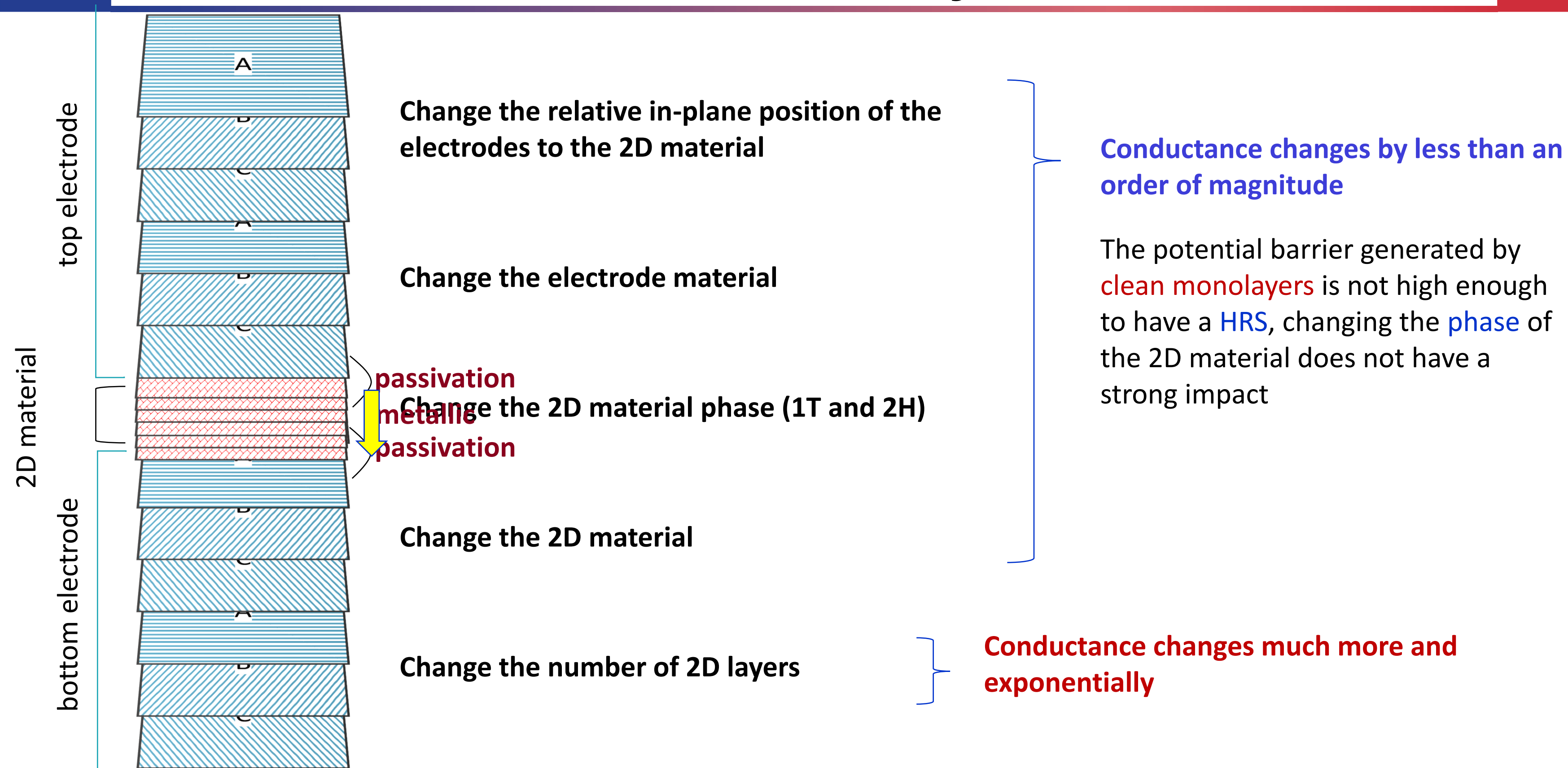
# Conductance in multilayers



The **contact layers are strongly coupled with electrodes** and determine the initial conductance.

Then, the **conductance decreases exponentially: interlayer tunneling**

# ...in summary



# Experimental conductance in the high resistance state

Experiments :  $10^{-6}$  -  $10^{-15}$   $\mu\text{S}/\text{\AA}^2$  range with no clear dependence neither on the channel thickness nor 2D material, but description compatible with tunnelling for the high resistance state, large variability.

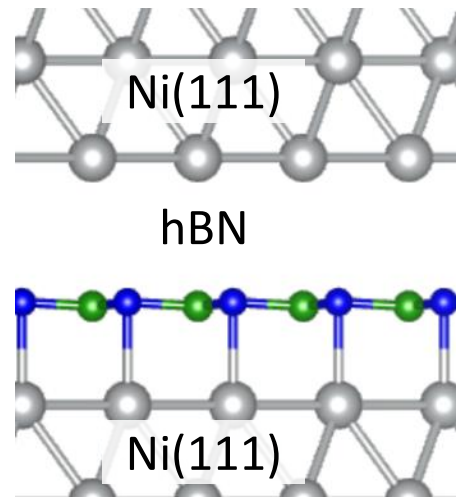
2D material	Electrodes	G ( $\mu\text{S}/\text{\AA}^2$ )	Reference
hBN (1L)	Ag    Ag	1.00E-15	Yang, ACS Nano 2024
hBN (1L)	Au   Cr    Cr   Au	1.00E-10	Wu, Adv. Mat. 2019
hBN (1L)	Ni    Au	1.90E-09	Li, APL 2022
hBN (3nm)	Au   Ti    Au	8.33E-14	Lin, APL 2019
hBN (6nm)	Au    Ti	4.00E-13	Zhuang, Adv. El. Mat. 2020
hBN (10nm)	Au    Au	1.11E-11	Pazos, Nat. Elect. 2024
hBN (9nm)	Au    Au	1.00E-06	Chen, Nanoscale 2023
hBN (5-7L)	Cu    Ti	5.00E-10	Pan, Adv. Funct. Mat. 2017
hBN (5-7L)	Au   Gr    Gr   Au	2.00E-12	Pan, Adv. Funct. Mat. 2017
MoS <sub>2</sub> (1L)	Au   Cr    Cr   Au	2.00E-07	Kim, Nat. Comm. 2018
MoS <sub>2</sub> (2.6nm)	Si   SiO <sub>x</sub>    Al	2.00E-13	Li, ACS Appl. Elec. Mat. 2024
MoS <sub>2</sub> (2L)	Au   Cr    Cu	1.39E-05	Xu, Nano Lett. 2019
MoS <sub>2</sub> - PVA (200nm)	Pt    Ag	3.29E-10	Liu, J. Phys. D 2022

2D material	Electrodes	G ( $\mu\text{S}/\text{\AA}^2$ )	Reference
MoS <sub>2</sub> (1.92nm)	Au   Cr    Cr   Au	1.00E-10	Gu, Adv. Elec. Mat. 2022
MoS <sub>2-x</sub> O <sub>x</sub> (30-40nm)	Gr    Gr	7.94E-06	Wang, Nat. Elect. 2018
MoS <sub>2</sub> (3-5L)	Au   Cr    Cr   Au	4.00E-08	Wu, RSC Adv. 2020
MoS <sub>2</sub> (1.4nm)	Au   Cr    Cr   Au	1.00E-06	Lee, ACS Nano 2024
MoS <sub>2</sub> (10nm)	Au    Ti   Au	4.00E-12	Krishnaprasad, ACS Nano 2022
MoS <sub>2</sub> (20nm)	Au    Au	5.56E-07	Yan, Adv. Elect. Mat. 2024
MoS <sub>2</sub> (300nm) MoO <sub>x</sub> (3nm)	Ag    Ag	1.51E-13	Bessonov, Nat. Mat. 2015
MoS <sub>2</sub> (5nm)	Au    Au	1.33E-06	Zhuang, Mat. Today Nano 2023
MoS <sub>2</sub> (0.75nm)	Au    Au	2.50E-14	Bhattacharjee, ACS App. Mate. & Int.2020
MoS <sub>2</sub> (2185nm)	Ag    Ag	2.50E-14	Xia, Nat. Comm 2024
MoS <sub>2</sub> (7-20nm)	Au    Ni   Au	3.13E-08	Song, J. of All. and Comp. 2021
MoS <sub>2</sub> (1L)	Au    Cr   Au	1.00E-07	Ge, Nano Lett. 2018

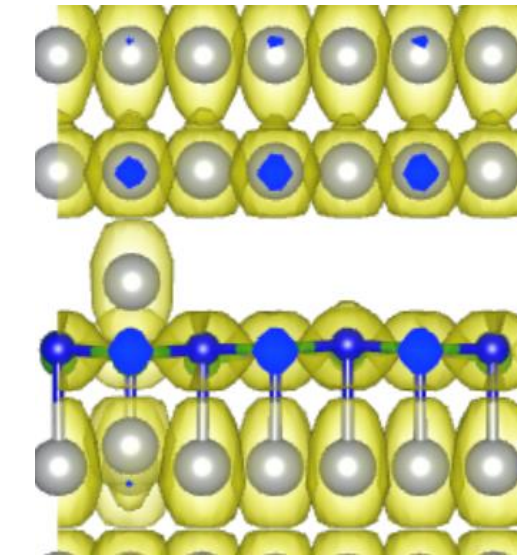
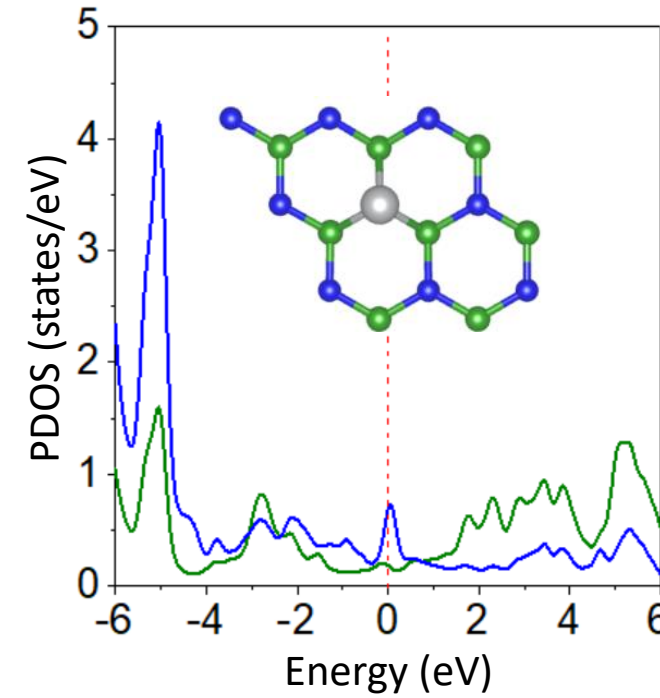
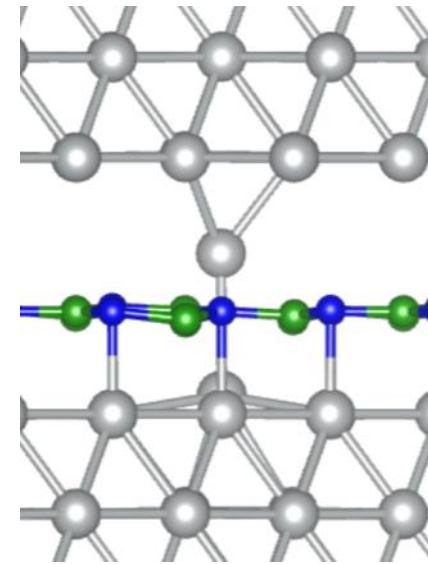
Simulations :  $1 \mu\text{S}/\text{\AA}^2$  range for monolayers and about one order of magnitude lost per added 2D layer and exponential dependence on the potential barrier widths.

Origin of the discrepancy: residues of polymers, oxides, multi-layered regions, roughness

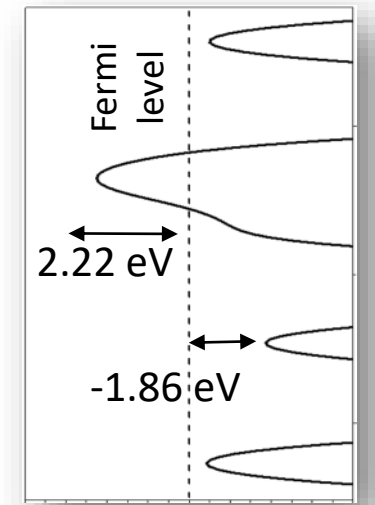
# Ni(111)/hBN/Ni(111): Metal-ion substitution



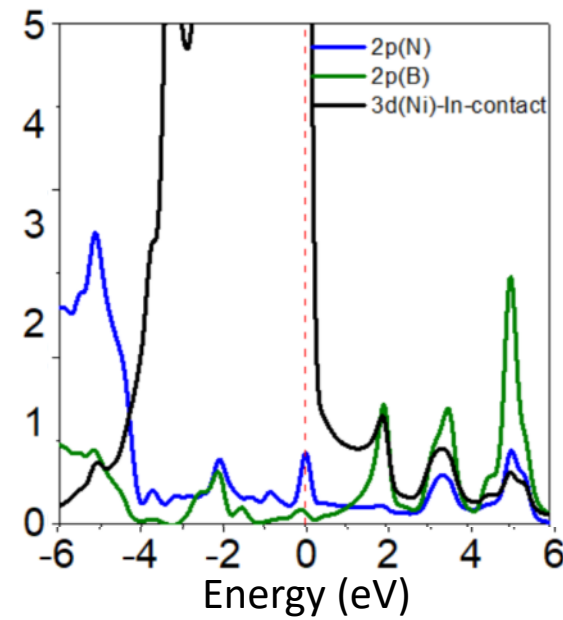
## N substitution



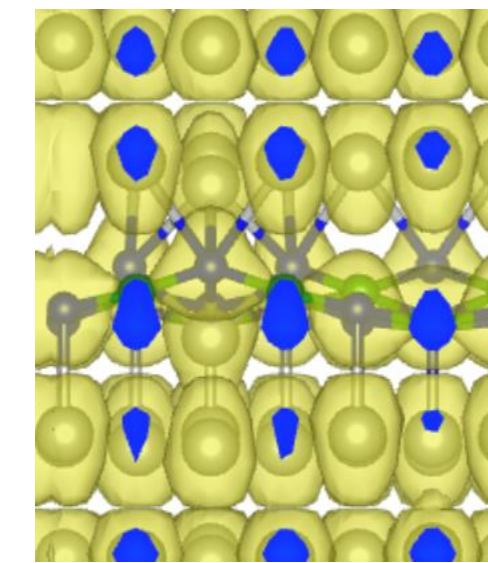
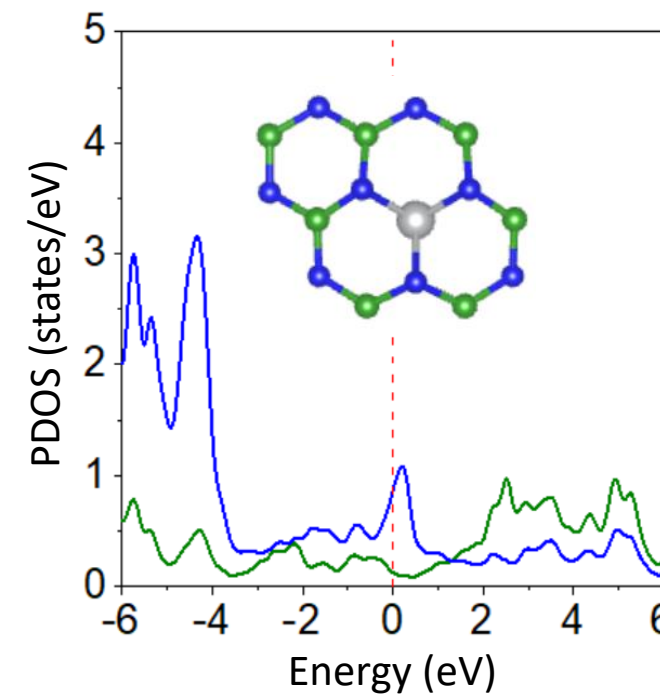
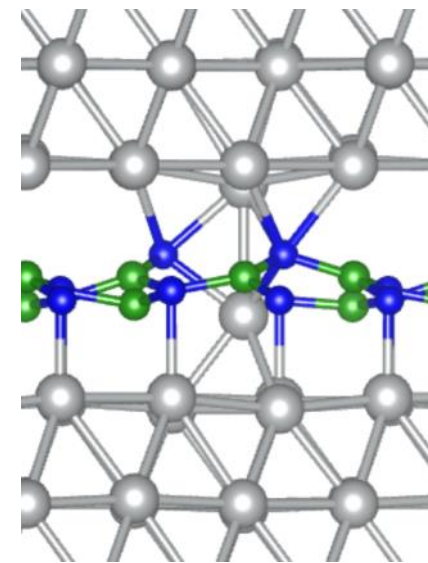
Charge distribution connecting electrodes via the Ni atom



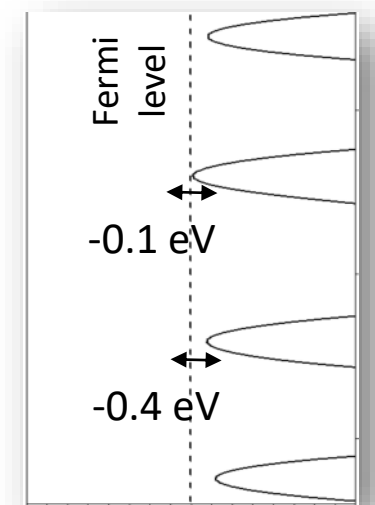
Average potential



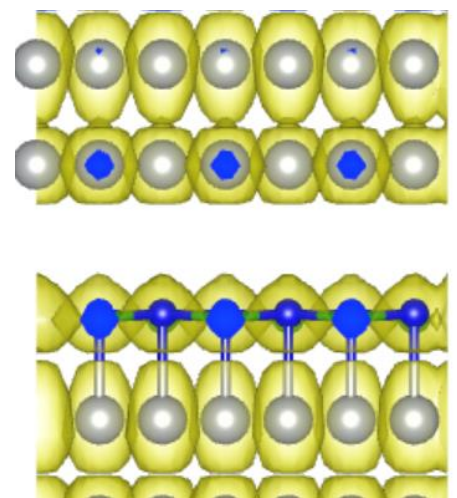
## B substitution



Higher states density in hBN



Average potential



# Perspectives

Extension of our approach to **all-2D-material memories** based on **ferroelectricity**, **ferromagnetism** and their combination in **multiferroic** devices.

**ferromagnetism**

**symmetry of 2D materials**

Mater. 11, 035019 (2024)

Study of ferroelectric and ferromagnetic properties in 2D materials (Janus), **number of layers**, **contact resistance**

Only 2D materials for flexibility and high integration

Multilevel memories for applications in neuromorphic computing

# Acknowledgement and some references



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Z. Kerrami  
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F. Triozon  
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G. Bigeard, Z. Kerrami, F. Triozon and A. Cresti, *Nanotechnology* **36**, 285201(2025)

Gaëlle Bigeard, “Quantum simulations of resistive switching in 2D material based stacks”, PhD manuscript (2025)

“Beyond-CMOS: State of the Art and Trends”, editor Alessandro Cresti, © ISTE Ltd 2023



# THANK YOU FOR YOUR ATTENTION!



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